

Search Notes**Application/Control No.**

10/644,755

Examiner

Anthony Weier

**Applicant(s)/Patent under
Reexamination**

LORTZ ET AL.

Art Unit

1794

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search plus		
426	423		
	330.3		
	330.4		
106	483	1/14/2008	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
426	422, 432		
	330.3		
	330.4		
106/483		1/14/2008	AW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PGPubText Search	1/14/2008	AW